

QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>10/062,047</u>	Prepared by <u>Lois Stone</u>	Tracking Number <u>5968396</u>	
Examiner-GAU <u>Siek - 2825</u>	Date <u>7/27/04</u>	Week Date <u>6/21/04</u>	
	No. of queries <u>1</u>	<u>RFW</u>	

JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

MESSAGE

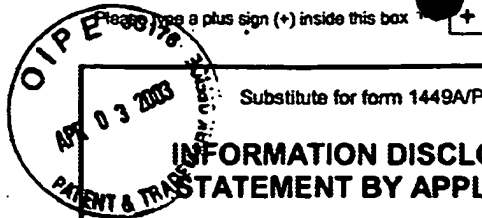
Please provide copies of the PTO-1449 forms with the citations either initialed or lined through. Copies provided for reference.

Thank you,

initials LS

RESPONSE

initials



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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet	1	of	2	Application Number	10/062,047
				Filing Date	1/31/02
				First Named Inventor	Steven Teig, et al.
				Group Art Unit	2825
				Examiner Name	
				Attorney Docket Number	SPLX.P0101

RELATED U.S. PATENT APPLICATIONS

Examiner [*] Initials	Cite No. ¹	U.S. Patent Application	Name of Patentee or Applicant of Cited Document	Date of Filing MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Serial Number			
	1.	10/062,017	Steven Teig & Asmus Hetzel	01-31-02	
	2.	10/061,459	Steven Teig & Asmus Hetzel	01-31-02	
	3.	10/062,014	Steven Teig & Asmus Hetzel	01-31-02	
	4.	10/062,044	Steven Teig & Asmus Hetzel	01-31-02	
	5.	10/066,264	Steven Teig & Asmus Hetzel	01-31-02	
	6.	10/066,188	Steven Teig & Asmus Hetzel	01-31-02	
	7.	10/062,992	Steven Teig & Asmus Hetzel	01-31-02	
	8.	10/061,474	Steven Teig & Asmus Hetzel	01-31-02	
	9.	10/061,719	Steven Teig & Asmus Hetzel	01-31-02	
	10.	10/066,456	Steven Teig & Asmus Hetzel	01-31-02	
	11.	10/062,993	Steven Teig & Asmus Hetzel	01-31-02	

U.S. PATENT DOCUMENTS

Examiner [*] Initials	Cite No. ¹	U.S. Patent Document	Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number Kind Code ² (if known)			
	12.	5,649,165	Jain et al.	07-15-97	
	13.	6,301,687 B1	Jain et al.	10-09-01	

Examiner Signature		Date Considered	
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^{*} EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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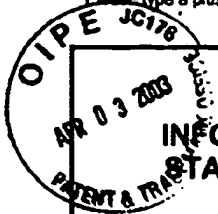
⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Approved for use through 10/31/2002. OMB 0651-0031
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet	2	of	2	Application Number	10/062,047
				Filing Date	1/31/02
				First Named Inventor	Steven Teig, et al.
				Group Art Unit	2825
				Examiner Name	
				Attorney Docket Number	SPLX.P0101

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner ¹ Initials	Cite No. ²	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ³
	14.	D. Jongeneel, R. Otten, Y. Watanabe and R. K. Brayton, Area and Search Space Control for Technology Mapping, 37 th Design Automation Conference, 86-91, 2000.	
	15.	Henrik Reif Andersen, An Introduction to Binary Decision Diagrams, October 1997 (minor revisions April 1998), 36 pp.	
	16.	Jerry Burch and David Long, Efficient Boolean Function Matching, Proc. ICCAD 1992, 408-411.	
	17.	John Fishburn, A Depth-Decreasing Heuristic for Combinational Logic; or How to Convert Ripple-Carry Adder into a Carry-Lookahead Adder or Anything In-Between, Proceedings of the 27 th Design Automation Conference, 361-364, 1990.	
	18.	Kamal Chaudhary and Massoud Pedram, A Near Optimal Algorithm for Technology Mapping Minimizing Area under Delay Constraints, Proceedings of the 29 th Design Automation Conference, 492-498, 1992.	
	19.	Kurt Keutzer, DAGON: Technology Binding and Local Optimization by DAG Matching, Proceedings of the 24 th Design Automation Conference, 341-347, 1987	
	20.	Randal Bryant, Symbolic Boolean Manipulation with Ordered Binary Decision Diagrams, CMU CS Tech Report CMU-CS-92-160.	
	21.	Uwe Hinsberger and Reiner Kolla, Boolean Matching for Large Libraries, Proceedings of the 35 th Design Automation Conference, 206-211, June 1998.	
	22.	Yuji Kukimoto, Robert K. Brayton, and Prashant Sawkar, Delay-Optimal Technology Mapping by DAG Covering, Dept. of Electrical Engineering and Computer Science, University of California, Berkeley, Strategic CAD Laboratories, Intel Corp., October 1997.	
	23.	Zbigniew J. Czech, et al., An Optimal Algorithm for Generating Minimal Perfect Hashing Functions, Information Processing Letters, 43(5); 257-264, October 1992	

Examiner Signature		Date Considered	
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